



# Run-III Dileptonic Top Quark Pair Production Cross-section Measurement Introduction

credits: TTXS members and FNAL staffs

# TTXS Facilitators



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# Introduction

“  $\sigma_{t\bar{t}}$  rises to **921 pb** at  $\sqrt{s} = 13.6$  TeV from 834 pb in Run 2.”

“We expect sensitivity on the order of  $\pm 5\%$  ( $\pm$  lumi).”

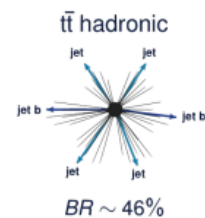
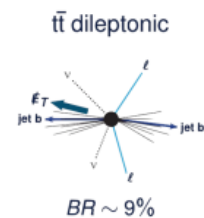
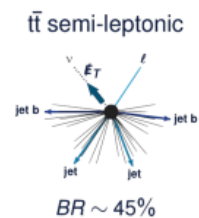
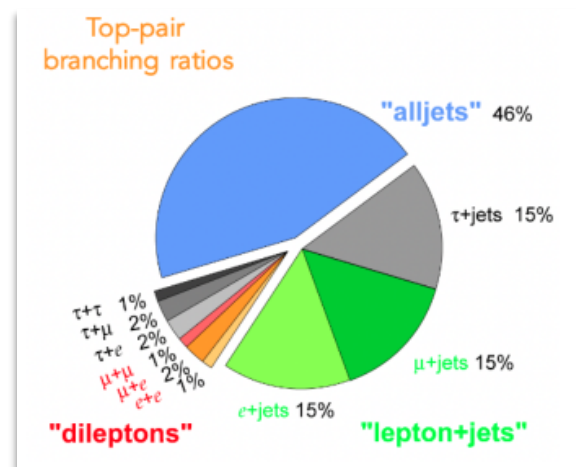
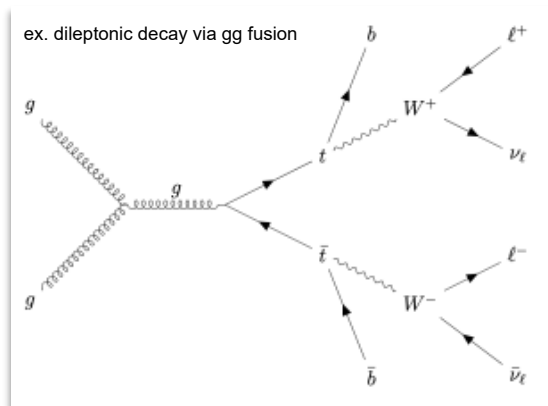
Top-antitop quark production cross-section is an important attribute to validate the Standard Model (SM) physics. It can also be used as a probe to access new physics among many observables provided by the LHC.

The CMS collaboration expects to gain 10% increase in the x-sec from 13 TeV to 13.6 TeV with PDF4LHC21 predictions. ([TOP-22-012](#))

# Top Pair Decay Channels

$t\bar{t}$  dileptonic production cross-section

$$\sigma \propto |\mathcal{M}(gg/qq \rightarrow t\bar{t} \rightarrow \ell^+ \nu b; \ell^- \bar{\nu} \bar{b})|^2$$



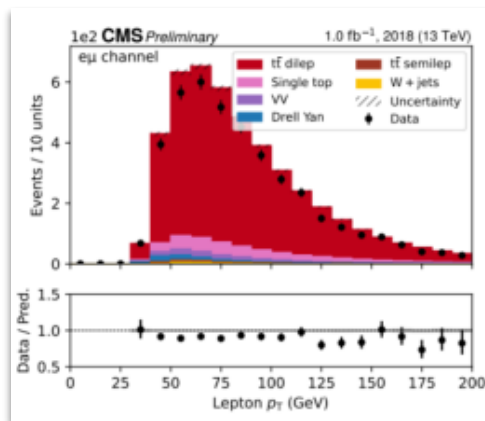
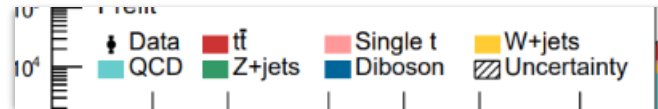
# Signal Selection

1. Lepton pair with opposite signs at high  $p_T$ 
  - a.  $ee$ ,  $e\mu$ ,  $\mu\mu$ ,  $e$ +jets,  $\mu$ +jets
2. Not including leptonic tau decays
3. At least 1 b-tagged jet

$\bar{q}q'$	electron+jets	muon+jets	tau+jets	all-hadronic
$\tau^-$	$e^-$	$\mu^-$	$\tau^-$	tau+jets
$\mu^-$	$e^-$	$\mu^-$	$\tau^-$	muon+jets
$e^-$	$e^-$	$\mu^-$	$\tau^-$	electron+jets
W decay	$e^+$	$\mu^+$	$\tau^+$	$q\bar{q}'$

# Background Events

1. V+Jets
2. SingleTop
3. QCD
4. Diboson
5. ...



## Data & MC Samples

Luminosity of  $1.23 \text{ fb}^{-1}$  of certified data from Era C (golden JSON from 16.08.)

MuonEG, Egamma, Muon DoubleMuon data stream [[Look up the definitions here](#)]

Single & Dilepton high level triggers (HLT) applied

# The ABCD Method

## Region A: Signal Region (SR)

- Meets both selection criteria (e.g., tight isolation and a certain jet multiplicity).
- Contains contributions from both signal and background.

## Region B: Background Region 1

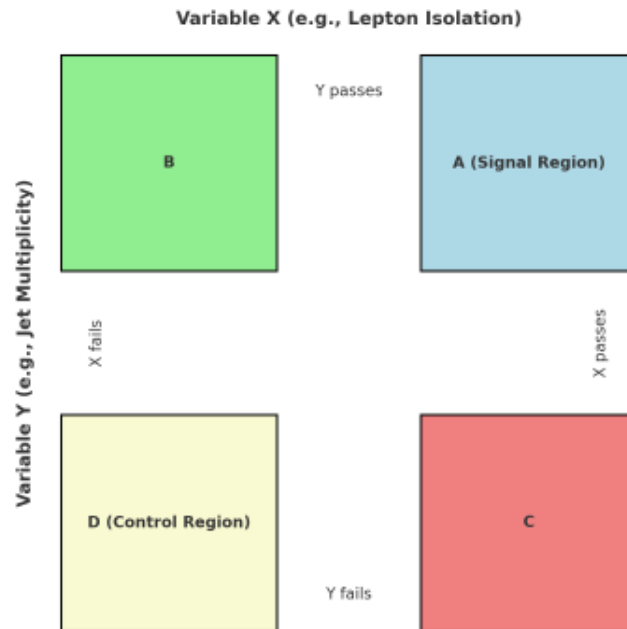
- Meets one selection criterion but fails the other (e.g., loose isolation).

## Region C: Background Region 2

- Fails the first criterion but meets the second.

## Region D: Control Region

- Fails both selection criteria.





## Scale Factors

1. Lumi SF  $SF_{lumi} = \frac{\sigma \times \mathcal{L}}{N_{Gen}}$

5. BTagging SF

1. Trigger SF  $SF_{Trigger} = \frac{\epsilon_{trigger}^{data}}{\epsilon_{trigger}^{MC}}$

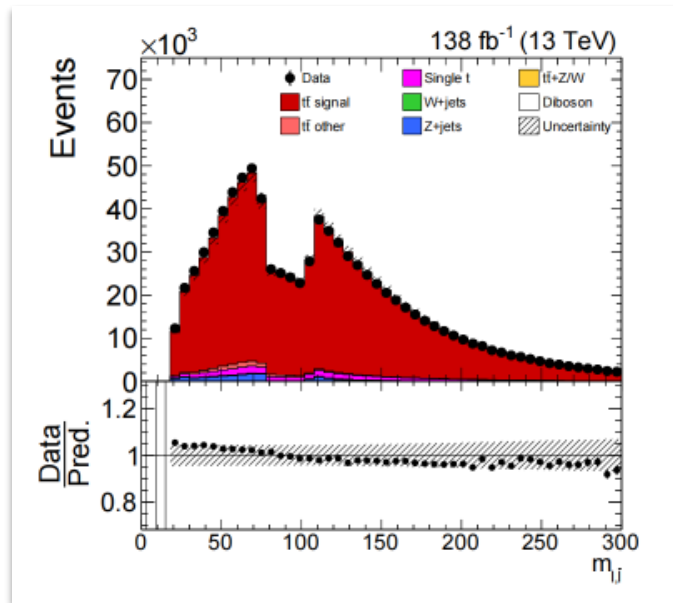
1. Non-prompt SF  $N_{NP}^{SR} = \left( N_{data}^{CR} - N_{MC}^{CR} \right) \times \frac{\left( N_{data}^{SR,1j} - N_{MC}^{SR,1j} \right)}{\left( N_{data}^{CR,1j} - N_{MC}^{CR,1j} \right)}$

1. Drell-Yan SF  $SF_{DY} = \frac{\left( N_{out}^{\geq 1b} \right)_{data}}{\left( N_{out}^{\geq 1b} \right)_{MC}} = \frac{\left( N_{in}^{\geq 1b} \right)_{data}}{\left( N_{in}^{\geq 1b} \right)_{MC}} \cdot \frac{\left( R_{in/out}^{0b} \right)_{MC}}{\left( R_{in/out}^{0b} \right)_{data}}$

# Event Selections

- Electrons:  $p_T > 35$  GeV,  $|\eta| < 2.4$ 
  - ◆ tight cut-based ID
  - ◆  $|\eta_{SC}|$  not in  $[1.444; 1.566]$
- Muons:  $p_T > 35$  GeV,  $|\eta| < 2.4$ 
  - ◆ tight cut-based ID, tight ISO
- $m_{\ell\ell} > 20$  GeV
- Z peak: remove  $76 \text{ GeV} < m_{\ell\ell} < 106$  GeV (ee and  $\mu\mu$  only)
  - ◆ No MET Cuts

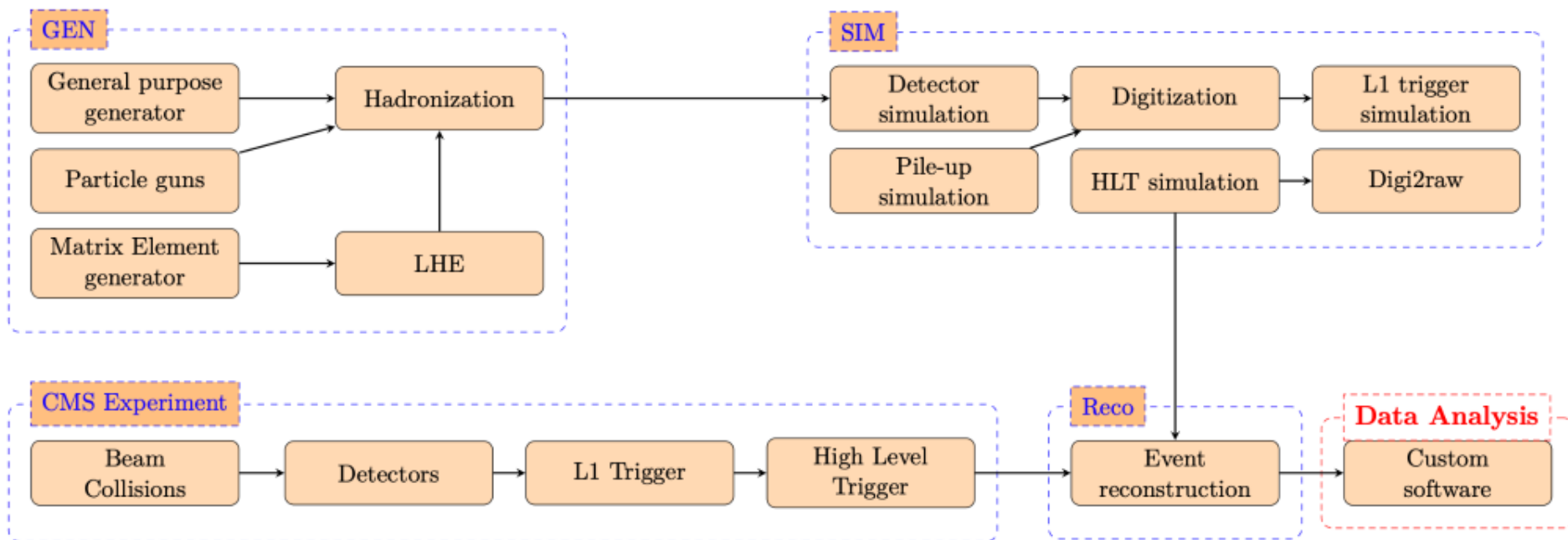
ex. excluded Z peak in mutual-flavor lepton pairs



[TOP-23-006]

# Jet Selections

- Charged Hadron Subtraction (CHS), Tight jet ID
- $|\eta| < 2.4$
- $p_T > 30 \text{ GeV}$



# Common Analysis Tools

## 1. Columnar Analysis in Python

- a. Pepper
- b. Coffea
- c. Uproot
- d. NanoAODSchema
- e. Awkward Array

## 2. Anaconda & Jupyter-lab

- a. A convenient UI
- b. Support many formats, as competitive as MS VisualStudio



[OpenAI image]

# Statistical Method

Likelihood fit via Combine Tool

$$\mathcal{L}_{\text{bin}} = \Gamma \left[ n_{\text{obs}}^{\text{bin}} \middle| r s^{\text{bin}}(\{\theta_i\}) + b^{\text{bin}}(\{\theta_i\}) \right] \times \prod_i p_i(\theta_i)$$

Overall Likelihood Function

$$\mathcal{L} = \prod_{\text{bin}} \mathcal{L}_{\text{bin}}$$

Poisson Distribution

$$\Gamma[n|\lambda] = \frac{\lambda^n e^{-\lambda}}{n!}$$

s - signal

b - background

$\{\theta_i\}$  - nuisance parameters

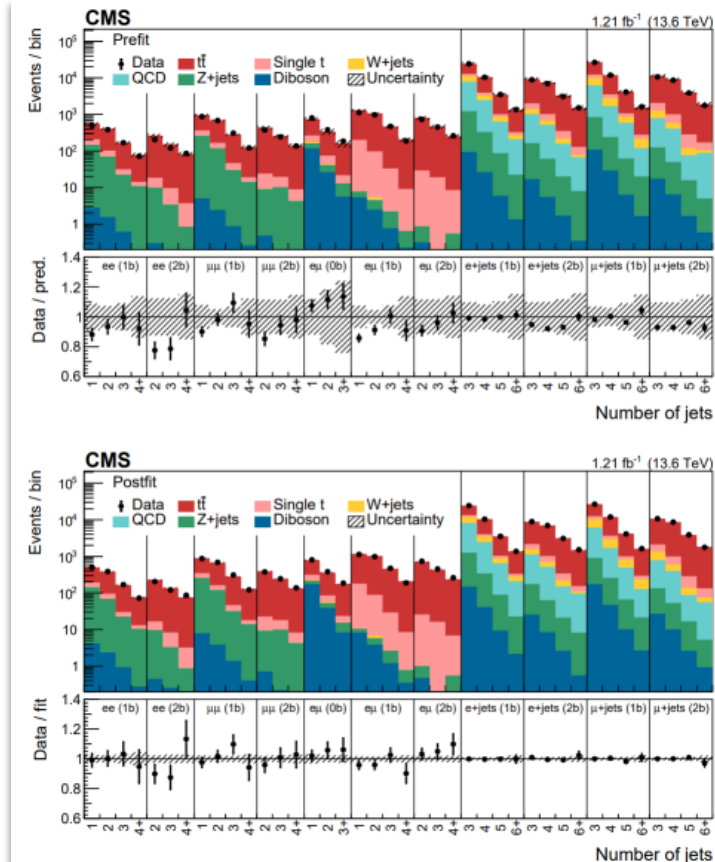
$p_i(\theta_i)$  - penalties

# Statistical Method

prefit (top) vs. postfit (bottom)

pay attention to

1. normalization changes
2. changes in uncertainties



[\[TOP-22-012\]](#)

# Statistical Method

Externalized: Lumi

Included in LL fit:

check out do\_syst\_table.py  
for the systematic uncertainty names

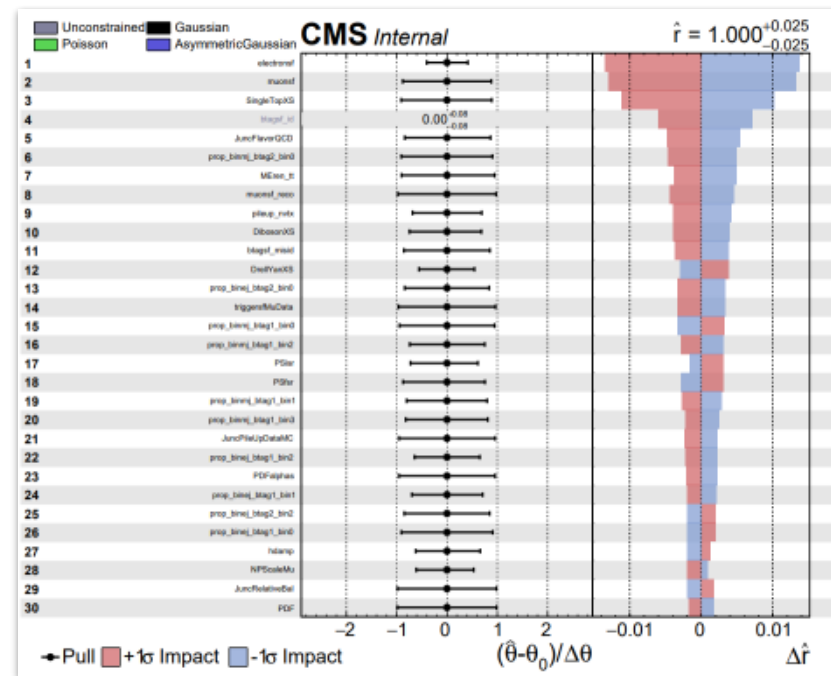
Category	Parameter	Implementation	Treatment	tt	Single t	Drell Yan	Diboson	W+jets
Dominant Experimental	Lepton ID	Unconstrained	Correlated	✓	✓	✓	✓	✓
	JES	Shape	Correlated	✓	✓	✓	✓	✓
	b-tag SF	Shape	Correlated	✓	✓	✓	✓	✓
	Light Mistag SF	Shape	Correlated	✓	✓	✓	✓	✓
	Pileup	Shape	Correlated	✓	✓	✓	✓	✓
	Trigger SF	Shape	Correlated	✓	✓	✓	✓	✓
Dominant Theory	PDF ( $+\alpha_s$ )	Normalized Shape	Correlated	✓	✓	✓	✓	✓
	ME Scale	Normalized Shape	Uncorrelated	✓	✓	✓	✓	✓
	PS Scale	Normalized Shape	Correlated	✓	✓	✓	✓	✓
	$h_{\text{damp}}$	Dedicated Sample	Signal Only	✓	—	—	—	—
	BG Cross Section	Normalization	Uncorrelated	✓	15%	20%	30%	30%



## Statistical Method

Summarize the effect of nuisance parameters on the best-fit value of the signal strength parameter  $\mathbf{r}$ .

A well-behaved fit typically has most pulls within  $\pm 1\sigma$ , indicating that the data reasonably constrain the nuisance parameters



[TOP-22-012]

# “It’s time to stop!”

Now we take a break and divide into two groups.

Group 1: Fill the histograms with lumi SF. Consider what samples to include in the control plots. Consider parton shower variation. Plot electron ID SF vs. nominal.

Group 2: Also fill the histograms with lumiSF. Consider pile-up reweighting. Plot muon ID SF vs. nominal.



Back Up

# Actual Stack Plots in AN

